Amendments to the Specification

Please amend the paragraph at page 4, line 14 through page 15, line 7, in the following manner:

The present invention provides an optical recording medium which comprises a transparent substrate; a recording layer having the main component of organic dyes; an optical reflective layer; and a protective layer, wherein the recording layer, the optical reflective layer, and the protective layer are formed on the substrate in this sequence, ~~recoding~~ recording at a recording linear velocity of 27.9m/s or more is possible, and the optical reflective layer comprises any one of Ag and an alloy mainly made from Ag The optical reflective layer is characterized in that the layer comprises any one of Ag and an alloy mainly made from Ag and a x-ray diffraction spectrum of the optical reflective layer satisfies the relational expression of $0.2 < I(200) / I(111) < 0.4$, in which I (111) is an intensity of the x-ray diffraction peak from (111) plane and I (200) is an intensity of the x-ray diffraction peak from (200) plane determined by x-ray diffraction based on $\theta - 2\theta$ method when the incidence angle relative to the surface of the optically transparent substrate being θ.

Please amend the paragraph at page 5, line 20 through page 6, line 3, in the following manner:

Film-formation of recordable optical discs are usually performed by forming a recording layer comprising organic dyes on a transparent substrate having guide grooves engraved thereon and by further forming a reflective layer and a protective layer on the recording layer. For discs using ~~adhesive materials~~ bonded discs like DVD, another (cover) substrate is further bonded on the protective layer through an adhesive layer.

Please amend the paragraph at page 8, lines 5-22, in the following manner:

The quality of the reflective layer can be checked by the numeric value of I (200) / [[I (111]] I(111) when I (111) is an intensity of the x-ray diffraction peak from (111)

plane and I (200) is an intensity of the x-ray diffraction peak from (200) plane determined by x-ray diffraction based on θ - 2θ method (one of the methods for evaluating thin films, as disclosed in Japanese Patent Application Laid-Open (JP-A) No. 07-110964) and when the incidence angle relative to the surface of the optically transparent substrate is θ. If the numeric value of I (200) / I (111) is 0.4 or more, the reliability of storage stability will increase but its recording properties will get worse, and if the numeric value of I (200) / I (111) is 0.2 or less, the reliability of storage stability will get worse but there will be no negative impacts on the recording properties. Hence, to satisfy both recording properties and reliability of storage stability, the numeric value of I (200) / I (111) should be $0.2 < I (200) / I (111) < 0.4$, and more preferably $0.21 \leq I (200) / I (111) \leq 0.39$. In addition, if sputtering gas-pressure is increased, the numeric value of I (200) / I (111) will increase.

Please amend the paragraph at page 9, lines 18-22, in the following manner:

The protective layer is usually has a thickness from about 3μm to about 15μm. Neither a too thin layer nor a too thick layer is preferable. If the thickness of the protective layer is too thin, the durability will lower, and if too thick, this will cause degradation of ~~machine~~ mechanical properties (bend).

Please amend Table 3 at page 15, in the following manner:

Table 3

	x-ray diffraction spectrum I(200)/I(111)	NdCu Content (% by weight)	Recording Properties		Reliability of Storage Stability (PI error max value)	
			Bottom Jitter	Reflectance	Before storing	After storing
~~Ex. 2~~ Ex. 1	0.21	0%	7.4%	50.2%	10	93
Ex. 4		1.8%	7.4%	49.1%	11	33
Ex. 5		2.3%	7.4%	48.4%	13	28